

Notice of References Cited	Application/Control No. 10/604,891	Applicant(s)/Patent Under Reexamination TANAKA, TAKUJI	
	Examiner Eugene Lee	Art Unit 2815	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,251,737 B1	06-2001	Lee, Tong-Hsin	438/307
	B	US-6,180,988 B1	01-2001	Wu, Shye-Lin	257/410
	C	US-6,433,371 B1	08-2002	Scholer et al.	257/288
	D	US-5,821,594 A	10-1998	Kasai, Naoki	257/410
	E	US-6,169,017 B1	01-2001	Lee, Tong-Hsin	438/585
	F	US-5,808,347 A	09-1998	Kurimoto et al.	257/408
	G	US-6,190,996 B1	02-2001	Mouli et al.	438/400
	H	US-6,018,179 A	01-2000	Gardner et al.	257/336
	I	US-6,015,746 A	01-2000	Yeh et al.	438/421
	J	US-6,051,861 A	04-2000	Togo, Mitsuhiro	257/340
	K	US-5,914,519 A	06-1999	Chou et al.	257/410
	L	US-6,124,177 A	09-2000	Lin et al.	438/305
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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